

Subclass	ISSUE CLASSIFICATION
Class	

FILED UNDER 35 U.S.C. § 351

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.
 SCANNED *MR* *TD3* *aa* *113*

PATENT DATE

APPLICATION NO. 09/856982	CONT/PRIOR D F	CLASS 356	SUBCLASS 237.4	ART UNIT 2877 2879	EXAMINER Nguyen Si
------------------------------	-------------------	--------------	-------------------	-------------------------------------	-----------------------

APPLICANTS
 Yoshio Yabe
 Osamu Nakamura
 Takashi Kiike
 Noboru Kudo

2877

TITLE

Method for inspecting a film of semiconductor wafer

PTO-2040
12/99

ISSUING OFFICE

TERMINAL DISCLAIMER <input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____ <input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	DRAWINGS Sheets Drawn _____ Filed Drawn _____ Print Fig. _____ (Assistant Examiner) (Date)			CLERK'S REQUIRED Total Charges _____ Total Charge for D/G _____	
	(Primary Examiner) (Date) (Legal Instruments Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
				ISSUE FEE	
				Amount Due _____	Date Paid _____
			ISSUE BATCH NUMBER		

WARNING:

The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-438A
(Rev. 6/99)

FILED WITH: ☐ DISK (ORF) ☐ FICHE ☐ CD-ROM
 (Attached in pocket on right inside flap)

(FACE)